Back Contact Chalcogenide Photovoltaics: CdSe/CdTe and CdS/CdTe

- D. Josell, R. Debnath, C. Hangarter, J.Y. Ha, J. Guyer National Institute of Standards and Technology, Gaithersburg, MD 20899-8554
- B.Y. Yoo and D.U. Kim, Hanyang University, Ansan, Korea

M.A. Sahiner, Christopher J. Reehil and William A. Manners, Seton Hall University, S. Orange, NJ 07079

I present back contact geometry chalcogenide photovoltaics that place the CdTe absorber layer at the front of the device to create an analog of silicon back contact devices. I detail fabrication of the threedimensionally structured devices starting with two interdigitated comb electrodes, followed by selective electrodeposition of n-type semiconductor on one electrode then deposition of p-type absorber over the entire device. A single patterning process thus permits differentiation of the two interdigitated combs into positive and negative electrodes in the electrodes-first, semiconductors-last process. Placement of the n-type semiconductor behind the CdTe absorber permits devices with n-type CdSe as well as the standard CdS (Fig. 1).



Fig. 1: A cross-section of a photovoltaic device with electrodeposited CdSe and CdTe showing a pair of adjacent wires from the positive and negative electrodes of the device with the composition distribution mapped using energy dispersive spectroscopy.¹

Short circuit current density (J_{sc}) in current vs voltage measurements under simulated AM1.5 illumination are interpreted through modeling of carrier transport and recombination. With electrodeposited CdSe and pulsed laser deposited (PLD) CdTe, J_{sc} exceeds 15 mA/cm² and efficiency exceeds 4% for electrode comb pitch of 2 µm.



Fig. 2 Current-voltage response of a CdSe-CdTe backcontact device exhibiting 3.1% efficiency under simulated A.M. 1.5 illumination.

External Quantum Efficiencies (EQE) exceeds 40% at energies above the CdTe absorption edge with current extraction decreasing only modestly even for illumination at 300 nm. This is consistent with removal of the CdS window layer found over the CdTe absorber in standard devices.



Fig. 3 External quantum efficiency of a CdSe-CdTe backcontact devices showing the fraction of light that generates current at the electrodes under zero bias.

Laser beam induced current (LBIC) measurements with submicrometer spatial resolution are detailed and used to understand device performance. Results are also compared to quantitative modeling, the model predictions capturing trends observed with variation of electrode comb dimensions as well as semiconductor type and quality.

Device performance exceeds the performance of CdS/CdTe pillar devices with far finer dimensions.

1. D.U. Kim, C.M. Hangarter, R. Debnath, J.Y. Ha, C. R. Beauchamp, M.D. Widstrom, J.E. Guyer, N. Nguyen, B.Y. Yoo, and D. Josell, Solar Energy Materials and Solar Cells **109**, 246 (2013).